

## Technical Program at a Glance

Time	Tuesday • April 9		Wednesday • April 10		Thursday • April 11
8:00 AM	Opening & Keynote  Plenary Session 1 on <b>Non-Volatile Memories</b> Six platform presentations		Parallel Session 3A <b>ESD &amp; Latchup</b> + 4 papers	Parallel Session 3C <b>Failure Analysis</b> four papers	Plenary Session 5 on <b>Process Induced Damage</b> 1 invited review + 4 papers
8:25 AM					
8:50 AM					
9:15 AM					
9:40 AM			<i>extra time to check out the exhibits</i>		
10:05 AM Break					
10:30 AM			3B <b>Compound Semiconductors I</b> 3 papers	3D <b>Product Reliability I</b> 3 papers	Panel Discussion <b>Product Qualification</b>
10:55 AM					
11:20 AM					
11:45 AM					
12:10 PM	Dielectrics: ESREF Best Paper				
12:35 PM					
1:00 PM					
1:25 PM					
1:35 PM					<b>SPECIAL TOPIC</b>
2:00 PM	Parallel Session 2A <b>Dielectrics I</b> four platform presentations	Parallel Session 2C <b>MEMS</b> 2 invited reviews + 2 papers	4A <b>Compound Semiconductors II</b> 3 papers	4C <b>Product Reliability II</b> 3 papers	Irradiation (Germicidal) <b>3 papers</b>
2:25 PM					
2:50 PM			4C <b>Device &amp;</b>	4D <b>Interconnects</b>	Plenary Session 6 on <b>Dielectrics II</b>
3:15 PM					
3:40:00 PM Break					
4:05 PM	2B <b>Hot Carriers</b> five platform presentations	2D <b>Assy/Pkg</b> 3 invited reviews +1 paper	<b>Process</b> 5 papers	1 invited review + 5 papers'	<b>5 papers</b>
4:30 PM					
4:55 PM					
5:20 PM					
5:45 PM					
6:10 PM					
6:35 PM					
7:00 PM	Symposium Reception with Jack Kilby & 15 poster presentations		Workshops - 7:30 pm		

← April 7, Sunday NIGHT additional SER Workshop - Panel Discussion